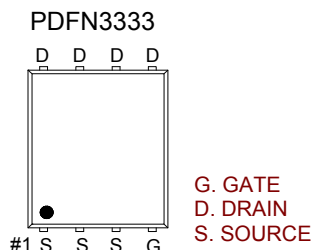


P -Channel High Density Trench MOSFET

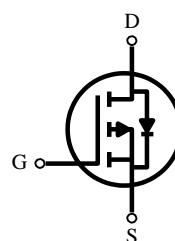
Features:

- Super high dense cell trench design for low RDS(on).
- Rugged and reliable.
- Surface Mount package.



PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(on)}$ (m Ω) Max	I_D
-50V	18 @ $V_{GS} = -32V$	-33A
	25 @ $V_{GS} = -6.5V$	



ABSOLUTE MAXIMUM RATINGS (TA = 25 °C unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DS}	-30	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous (Note 1)	I_D	Tc=25°C	-33
		Tc=70°C	-22
Pulsed Drain Current (Note 2)	I_{DM}	-108	A
Avalanche Current (Note 2)	I_{AS}	L = 0.1mH	-20
Single Pulse Avalanche Energy (Note 2)			E_{AS}
Maximum Power Dissipation (Note 1)	P_D	Tc=25°C	23
		Tc=70°C	9.2
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

TYPICAL THERMAL CHARACTERISTICS

Thermal Resistance	Symbol	Typical	Maximum	Units
Thermal Resistance Junction-to-Case (Note 1)	$R_{\theta JC}$		5.6	°C/W
Thermal Resistance, Junction-to-Ambient (Note 1)	$R_{\theta JA}$		62.5	°C/W

Note :

1. The value of $R_{\theta JA}$ is measured with the device mounted on 1 in FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ C$. The value in any given application depends on the user's specific board design. The current rating is based on the $t \leq 10s$ thermal resistance rating

2. Repetitive rating, pulse width limited by junction temperature

3. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to lead $R_{\theta JL}$ and lead to ambient

ELECTRICAL CHARACTERISTICS (TA = 25 °C unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} = 0V , I _D = -250uA	-30			V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = -24V , V _{GS} = 0V , T _j = 25°C			-1	uA
		V _{DS} = -24V , V _{GS} = 0V , T _j = 55°C			-30	
Gate-Body Leakage	I _{GSS}	V _{GS} = ±20V , V _{DS} = 0V			±100	nA
ON CHARACTERISTICS						
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250uA	-1	-1.5	-2.5	V
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = -10V , I _D = -12A		13	18	mΩ
		V _{GS} = -4.5V , I _D = -9A		17	25	mΩ
Forward Transconductance (Note 3)	g _{fs}	V _{DS} = -10V , I _D = -12A		21		S
DYNAMIC CHARACTERISTICS						
Input Capacitance	C _{ISS}	V _{DS} = -15V , V _{GS} = 0V f = 1.0MHz		1420		pF
Output Capacitance	C _{OSS}			202		pF
Reverse Transfer Capacitance	C _{RSS}			187		pF
Gate Resistance	R _g	V _{DS} = -15V , V _{GS} = 0V , f = 1.0MHz		6		Ω
SWITCHING CHARACTERISTICS						
Turn-On Delay Time	td _(ON)	V _{DD} = -15V , V _{GS} = -10V R _{GS} = 6Ω , I _D = -12A		13		nS
Rise Time	tr			21		nS
Turn-Off Delay Time	td _(OFF)			62		nS
Fall Time	tf			19		nS
Total Gate Charge (4.5V)	Q _g			12		nC
Total Gate Charge (10V)	Q _g	V _{DS} = -15V , V _{GS} = -10V , I _D = -12A		28		nC
Gate-Source Charge	Q _{gs}			5.4		nC
Gate-Drain Charge	Q _{gd}			8.1		nC
DRAIN-SOURCE DIODE CHARACTERISTICS						
Continuous Current	I _S				-21	A
Diode Forward Voltage	V _{SD}	V _{GS} = 0V , I _S = I _F		-0.8	-1.25	V

Note :

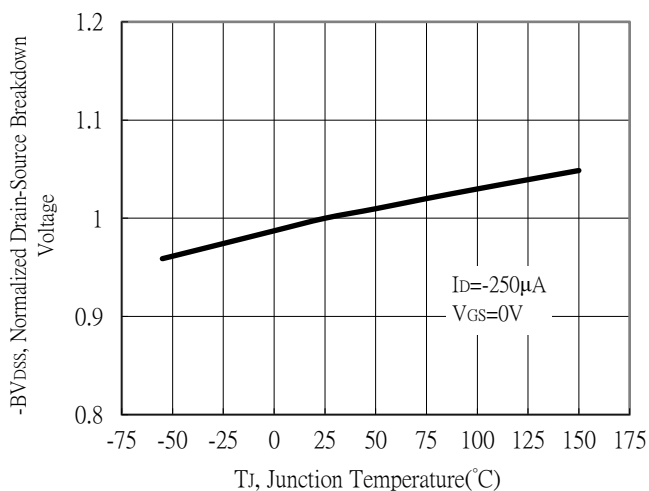
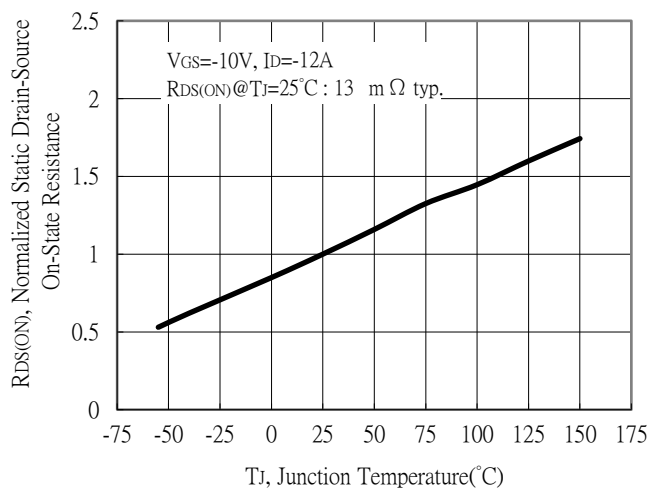
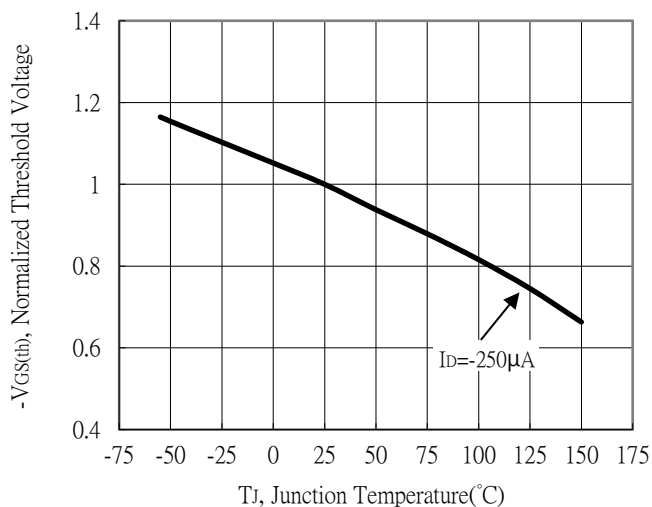
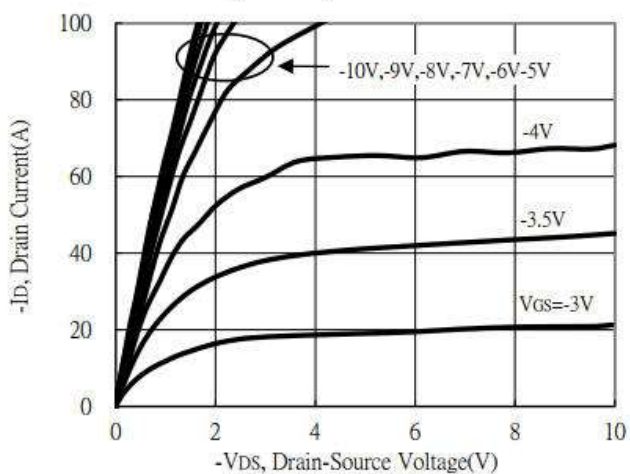
4. The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.

5. These tests are performed with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with T curve provides a single pulse rating

6. The current rating is based on the t ≤ 10s thermal resistance rating.

7. EAR and IAR ratings are based on low frequency and duty cycles to keep T_j=25C

Typical Output Characteristics



Gate Charge Characteristics

